

# In-situ inspection for Advanced Manufacturing

Septembre 2025 Quality management in AM, OPI HEPIA Genève Bernard Revaz

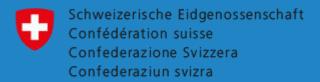


#### Bernard Revaz, CEO

Jonatan Wicht, Appl. Eng. Alain Berthoud, Mech. Eng. Yannick Bianchi, Data Scientist May 20, 2025

info@amiquam.ch
AMiquam SA
2, route Cité Ouest
CH-1196 Gland, Switzerland
www.amiquam.ch
https://www.linkedin.com/company/amiquam

+41 77 401 17 48



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Office for Economic Affairs and Innovation (SPEI)





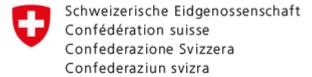




### Who we are

AMiquam

- Company developing in situ inspection for advanced manufacturing (metal PBF-LB)
- To reduce inspection costs and delays
- Founded in 2020 as a spin-off from ETH and Sensima, an NDT company
- Project with inspire, Fraunhofer, ETH, ESA, MTC, + other research centers
- Active commercial projects in Aerospace, Medtech, and Energy sectors
- Contribute to new industry standards ASTM/ISO, SAE ARP
- Designs approved by machine manufacturers, with full product integration achieved with GFMS (DMP350)
- Pre-approved for F-35 offset program (LPBF heat exchanger + blade repair)



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innovation across borders



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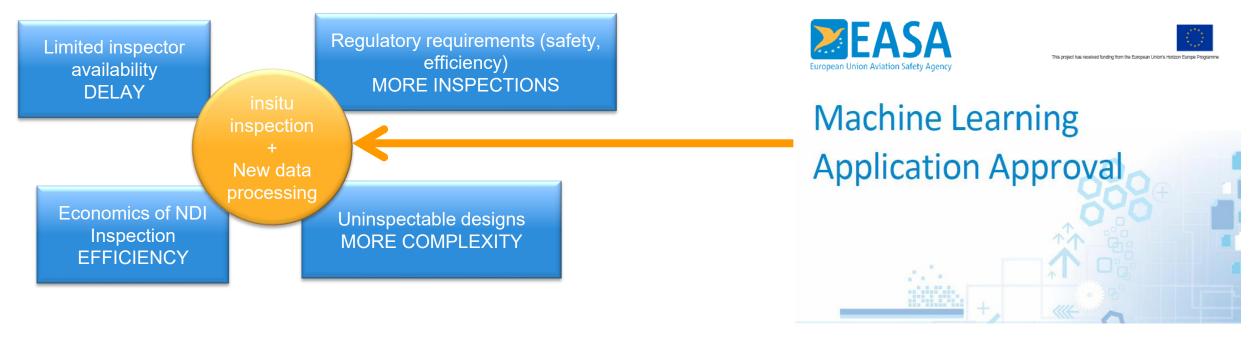






# AMIQUAM: Solving the bottleneck of inspection for safety critical metal parts





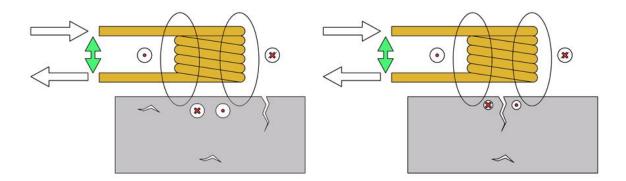
#### in situ inspection for Advanced Manufacturing

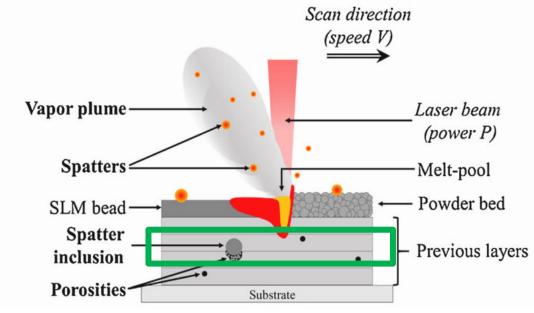
- Projects in LPBF, DED, WAAM, grinding rectification, EDM
- AMiquam supplier of ARIANE 6 (in situ NDT for shot peening + FSW) and other major organisations
- Platform for Advanced Manufacturing in situ inspection: reduce production waste/resources + delivery delays
- Key components: miniaturized NDT electronics (ECT) integration/interfacing solutions automated inspection analysis

# Eddy Currents



- Principles: ac magnetic fields generate currents in the part
- Advantages of EC for metal LPBF: non contact, integration, subsurface
- Purpose of examination: discontinuities and more
- Standardisation efforts for AM: ASTM/ISO, SAE ARP
- Detection limits: PoD









Expedite part certification	NDT data available at the end of the process, certification process can start immediately (remotely if necessary)	
Reduce human effort required for part certification	Using pre-processing and assisted defect recognition tool a table of indications is generated that is reviewed by the inspector	
Reduce costs for NDT	From \$1'000-2'000 with CT to \$250-500 with in situ inspection	
Adhere to existing standard	Compliant with established standards of the space/aviation/defense industry MIL-HDBK-1823A2009, ISO15548, ISO 77.040.20, ISO 9712:2021	
Reduce use of CT scans	Complement or replace CT scans	
Enable inspection of "uninspectable" parts	In-situ inspection enable the inspection of parts that are not accessible to inspection after the fabrication	

# Scope of EC inspection



ISO 15549, purpose of examination	Application to metal PBF-LB	Project example
to reveal discontinuities in the product which could affect its fitness for purpose;	See ASTM 3166 (cracks, pores, lack of fusion, inclusions, etc), rogue flaws	Inspire, DILAPRO, MTC, ESA,
to measure the thickness of coatings or layers;	Monitoring of process, SPC	Software development
to measure other geometric characteristics;	Detection of cold cracking, prevent part failure, lattice integrity, heat exchangers, hybrid manufacturing	Volum-e, HESSO-VS, TH Rosenheim
to measure metallurgical or mechanical properties of the product+sort products	In situ monitoring of mechanical performance, reduce coupon mechanical tests	Fieldmade
to measure the conductivity and/or permeability of the product;	Measure porosity	EOS, Zeiss, Constellium, Rosswag
+ to measure residual stress	Prevent part failure, reduce HIP	Uni Pavia

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## Existing standards + new standard

#### **EC NDT standards**



ASTM E1004-17

ASTM E376-19

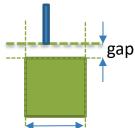
ASTM E1476 E556



General applications of EC for NDT



Electrical conductivity measurements



geometrical defects stress induced deformation



Metals Identification, Grade Verification, and Sorting

#### AM specific requirements

- Positioning the sensors as required by the inspection procedure
- Verifications needed: No impact on fabrication process, No spurious signals caused by cable motion and recoater vibrations
- Lift-off frequency calibration procedure
- Additional calibration samples for subsurface pores
- Impact of the residual stress on the defect assessment
- Features of the software used to analyse the data and generate the report
- Cancelation of powder signal, when powder is over the sample ction of pore/defect healing

In-process inspection standard for AM

ASTM 3166, 52930, 52906, 52905

AM guides, practice, standards

### Existing standards

ASTM 3166: Standard Guide for Nondestructive Examination of Metal Additively Manufactured Aerospace Parts After Build:

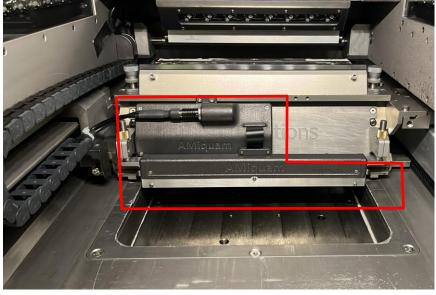
52930:Additive manufacturing — Qualification principles — Installation, operation and performance (IQ/OQ/PQ) of PBF-LB equipment

52906: Non-destructive testing — Intentionally seeding flaws in metallic parts

52905: Non-destructive testing and evaluation — Defect detection in parts

### In situ ECT for LPBF





W2-ECA

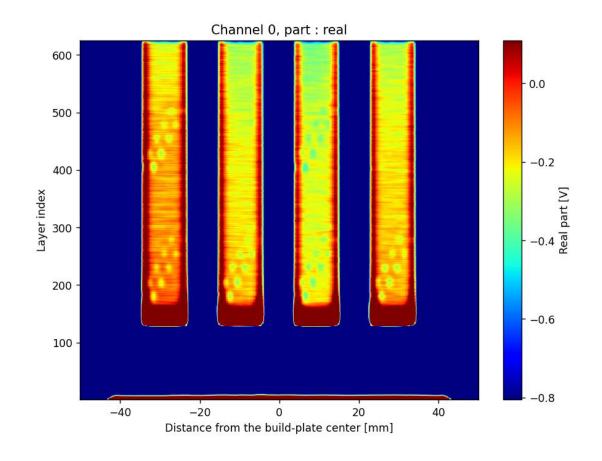
Machine agnostic
Fully reversible installation
No penalty on process
Compatible with multilaser
Modular design (n x 240mm)

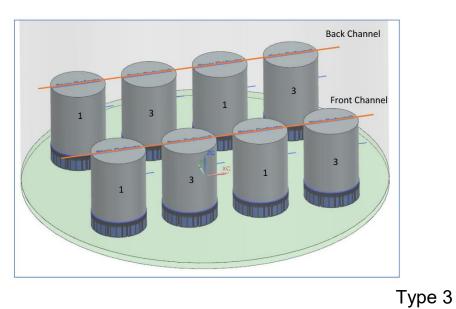
Conservative design Focus on integration

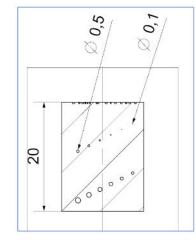
Validation, screening

W1-2/4 sensors

### Defect detection







Defects from 1mm to 0.5mm

Defects from 1mm to 0.1mm

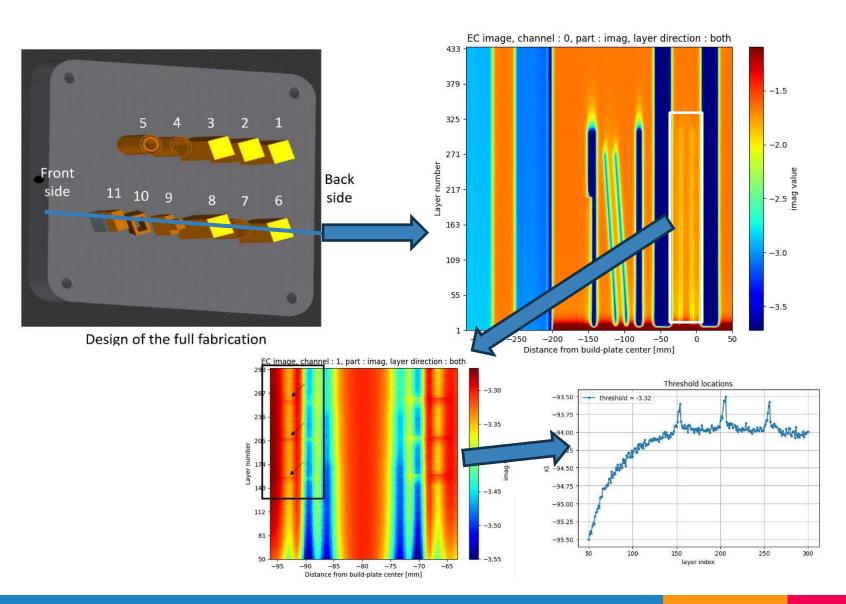
### Results: Defect detection



LPBF process based on digital information

ECT images are strongly redundant

Indications can be selected with algorithms



# Sensitivity



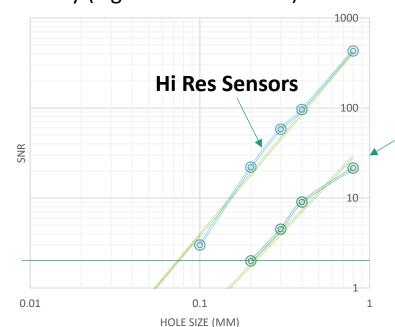
AMiquam sensors/electronics sensitivity to pore (mm), conditions: milled/casted samples

• 0.2mm (sensor: ABS56)

SNR=2

<0.1mm (sensor: SR25) pore detection</li>

Sensitivity (Signal to noise Ratio) in ideal case:



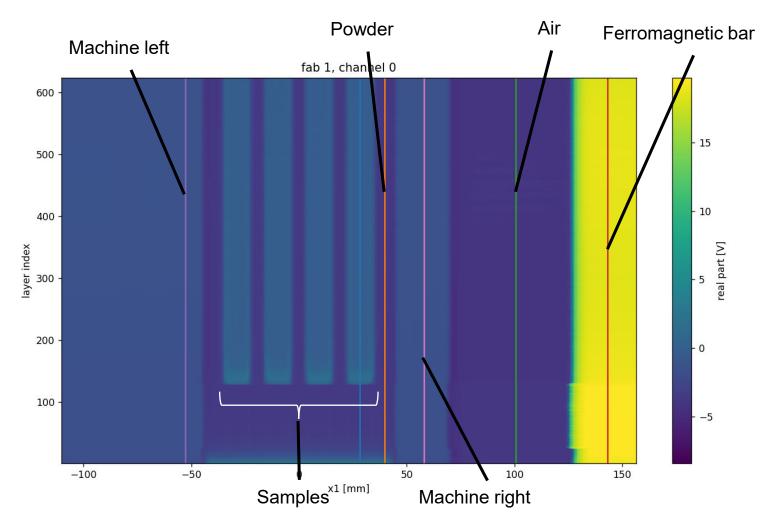
Sensors used in products W1/W2



Sensitivity (SNR = 2)	Sensor used in product W1/W2	High res sensors (not in products yet)
Sensitivity (flat homogeneous samples)	0,2 mm	0,07 mm
Sensitivity (in situ inspection)	0,4 mm	?



### EC cross section view (channel 0)

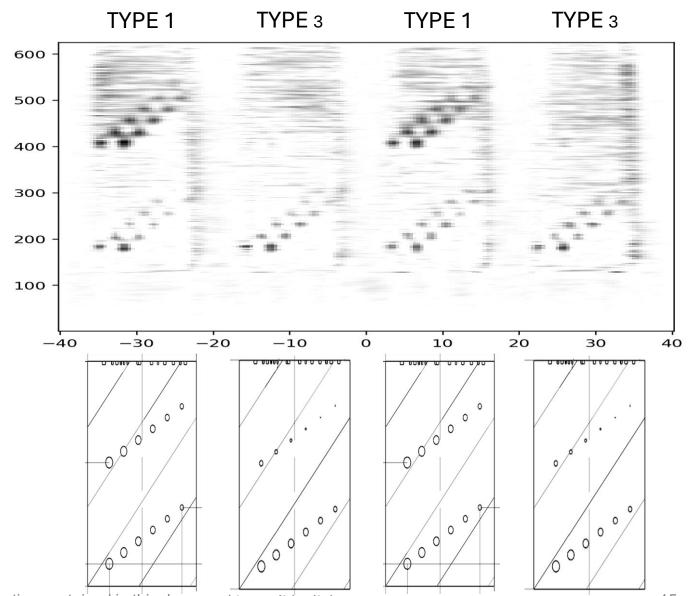


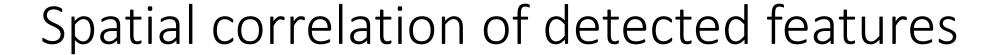
### Feature analysis and detection



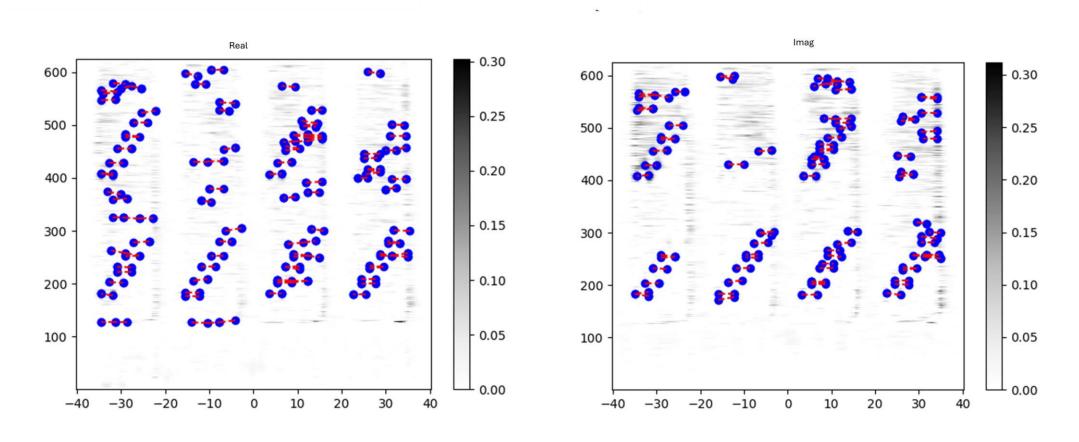
Algorithms transform the complex EC signals into:

- 1. relevant features dark dots
- 2. process variations thin horizontal lines









Each pore causes a double dot structure related to the "point spread function" of the sensor. This structure can be used to separate the defect from the process variations ("background noise").



### Detection limits

Some 0.2mm pores show the double peak structure

#### **Further work**

- Improvement of measurement parameters
  - Frequency, data acquisition rate, sensor design
- Data processing
  - Phase optimisation, deconvolution
- CT scans to assess the "quality" of the pores

Pore diameter [mm]	Feature size [mV]
1	96
0.9	94.6
0.8	80
0.7	86.7
0.5	29.3
0.4	36.4
0.3	17.1
0.2	10

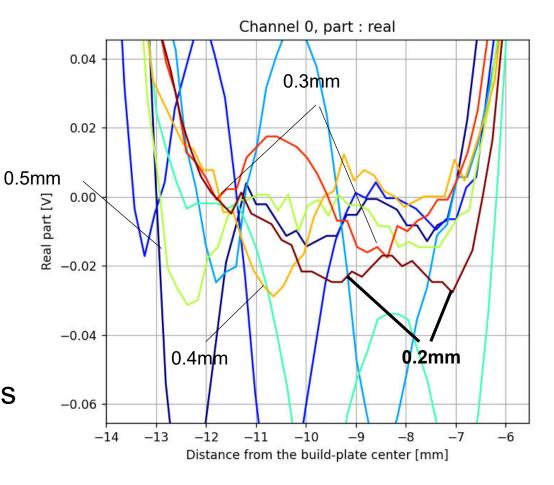


#### Detection limits

the double peak structure of 0.2mm pores is detected in the spatial EC traces

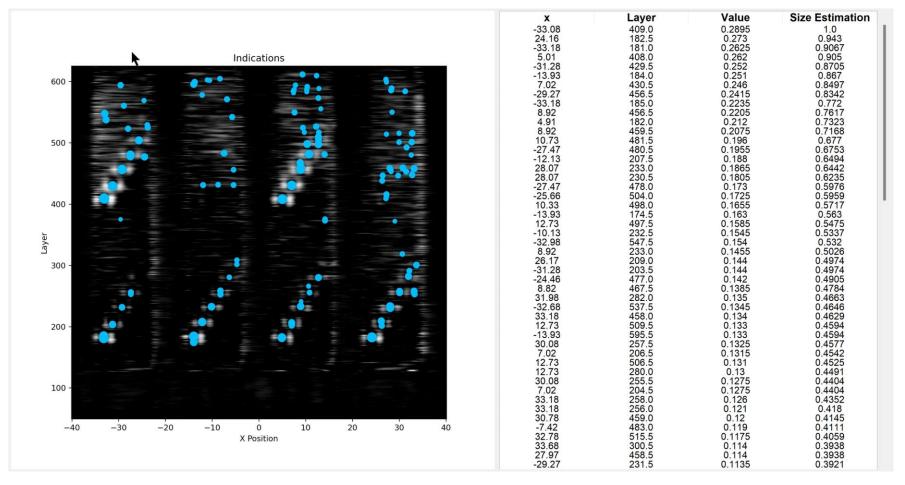
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- CT scans to assess the "quality" of the pores



### Indications with size estimation





A list of indication is automatically generated to be reviewed by a certified inspector The blue dots correspond to the location of the defects based on the deconvolution of the white dot pairs

# Thanks!

AMiquam SA 2, route Cité Ouest 1196 Gland, Switzerland